

Search Notes

Application/Control No.

10/751,523

Examiner

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Applicant(s)/Patent under
Reexamination

YOSHIDA, TAKAKI

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	6,10,13,14	9/16/2006	PK
702	69,79,65	9/16/2006	PK
703	16,19	9/16/2006	PK
324	523,532	9/16/2006	PK
324	537	9/16/2006	PK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
716	6,10,13	9/16/2006	PK
716	14	9/16/2006	PK
702	69,79,65	9/16/2006	PK
USPGPUB (see attached) 703/16,19; 324/523,532,537		9/16/2006	PK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS (EAST) --USPAT, USPGPUB Cls/Sub searched: 716/1-18; 702/79,69,64-65,125,176; 324/522-524,532-533,537 (see attached)	9/16/2006	PK
--USPAT, USPGPUB (continued) Cls/sub searched: 703/14-16,19 (see attached)	9/16/2006	PK
--EPO, JPO, IBM TDB, Derwent (see attached)	9/16/2006	PK
IEE/IEEE Xplore (see attached)	9/15/2006	PK